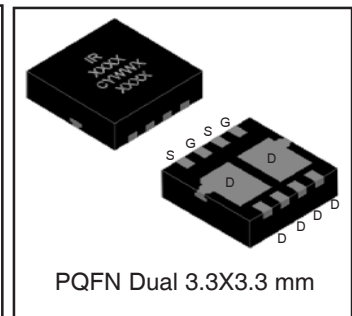
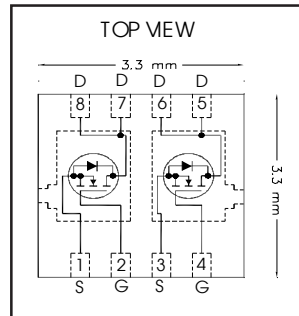


$V_{DS}$	<b>100</b>	<b>V</b>
$V_{GS\ max}$	<b>± 20</b>	<b>V</b>
$R_{DS(on)\ max}$ (@ $V_{GS} = 10V$ )	<b>195</b>	<b>mΩ</b>
$Q_g\ typ$	<b>4.2</b>	<b>nC</b>
$I_D$ (@ $T_{c(Bottom)} = 25^\circ C$ )	<b>3.4</b> Ⓣ	<b>A</b>

HEXFET® Power MOSFET



**Applications**

- DC-DC Primary Switch
- 48V Battery Monitoring

**Features and Benefits**

**Features**

Low $R_{DS(on)}$ (<195mΩ)
Low Thermal Resistance to PCB (< 12°C/W)
Low Profile (<1.2mm)
Industry-Standard Pinout
Compatible with Existing Surface Mount Techniques
RoHS Compliant Containing no Lead, no Bromide and no Halogen
MSL1, Industrial Qualification

results in  
⇒

**Benefits**

Lower Conduction Losses
Enable better thermal dissipation
Increased Power Density
Multi-Vendor Compatibility
Easier Manufacturing
Environmentally Friendlier
Increased Reliability

Orderable part number	Package Type	Standard Pack		Note
		Form	Quantity	
IRFHM792TRPBF	PQFN Dual 3.3mm x 3.3mm	Tape and Reel	4000	
IRFHM792TR2PBF	PQFN Dual 3.3mm x 3.3mm	Tape and Reel	400	EOL notice # 259

**Absolute Maximum Ratings**

	Parameter	Max.	Units
$V_{DS}$	Drain-to-Source Voltage	100	V
$V_{GS}$	Gate-to-Source Voltage	± 20	
$I_D @ T_A = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	2.3	A
$I_D @ T_A = 70^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	1.8	
$I_D @ T_{C(Bottom)} = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	4.8 Ⓣ	
$I_D @ T_{C(Bottom)} = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	3.1	
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ (Wirebond Limited)	3.4 Ⓣ	
$I_{DM}$	Pulsed Drain Current Ⓣ	14	
$P_D @ T_A = 25^\circ C$	Power Dissipation Ⓣ	2.3	W
$P_D @ T_{C(Bottom)} = 25^\circ C$	Power Dissipation Ⓣ	10.4	
	Linear Derating Factor Ⓣ	0.018	W/°C
$T_J$	Operating Junction and	-55 to + 150	°C
$T_{STG}$	Storage Temperature Range		

Notes Ⓣ through Ⓣ are on page 9

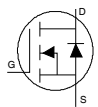
**Static @ T<sub>J</sub> = 25°C (unless otherwise specified)**

	Parameter	Min.	Typ.	Max.	Units	Conditions
BV <sub>DSS</sub>	Drain-to-Source Breakdown Voltage	100	—	—	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA
ΔBV <sub>DSS</sub> /ΔT <sub>J</sub>	Breakdown Voltage Temp. Coefficient	—	0.11	—	V/°C	Reference to 25°C, I <sub>D</sub> = 1.0mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance	—	164	195	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 2.9A ③
V <sub>GS(th)</sub>	Gate Threshold Voltage	2.0	3.0	4.0	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 10μA
ΔV <sub>GS(th)</sub>	Gate Threshold Voltage Coefficient	—	-8.2	—	mV/°C	
I <sub>DSS</sub>	Drain-to-Source Leakage Current	—	—	20	μA	V <sub>DS</sub> = 100V, V <sub>GS</sub> = 0V
		—	—	250	mA	V <sub>DS</sub> = 100V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 125°C
I <sub>GSS</sub>	Gate-to-Source Forward Leakage	—	—	100	nA	V <sub>GS</sub> = 20V
	Gate-to-Source Reverse Leakage	—	—	-100		V <sub>GS</sub> = -20V
g <sub>fs</sub>	Forward Transconductance	3.5	—	—	S	V <sub>DS</sub> = 50V, I <sub>D</sub> = 2.9A
Q <sub>g</sub>	Total Gate Charge	—	4.2	6.3	nC	V <sub>DS</sub> = 50V V <sub>GS</sub> = 10V I <sub>D</sub> = 2.9A
Q <sub>gs1</sub>	Pre-V <sub>th</sub> Gate-to-Source Charge	—	0.7	—		
Q <sub>gs2</sub>	Post-V <sub>th</sub> Gate-to-Source Charge	—	0.3	—		
Q <sub>gd</sub>	Gate-to-Drain Charge	—	1.3	—		
Q <sub>godr</sub>	Gate Charge Overdrive	—	1.9	—		
Q <sub>sw</sub>	Switch Charge (Q <sub>gs2</sub> + Q <sub>gd</sub> )	—	1.6	—		
Q <sub>oss</sub>	Output Charge	—	6.7	—	nC	V <sub>DS</sub> = 16V, V <sub>GS</sub> = 0V
R <sub>G</sub>	Gate Resistance	—	1.6	—	Ω	
t <sub>d(on)</sub>	Turn-On Delay Time	—	3.4	—	ns	V <sub>DD</sub> = 50V, V <sub>GS</sub> = 10V I <sub>D</sub> = 2.9A R <sub>G</sub> = 1.8Ω
t <sub>r</sub>	Rise Time	—	4.7	—		
t <sub>d(off)</sub>	Turn-Off Delay Time	—	5.2	—		
t <sub>f</sub>	Fall Time	—	2.6	—		
C <sub>iss</sub>	Input Capacitance	—	251	—	pF	V <sub>GS</sub> = 0V V <sub>DS</sub> = 25V f = 1.0MHz
C <sub>oss</sub>	Output Capacitance	—	31	—		
C <sub>rss</sub>	Reverse Transfer Capacitance	—	13	—		

**Avalanche Characteristics**

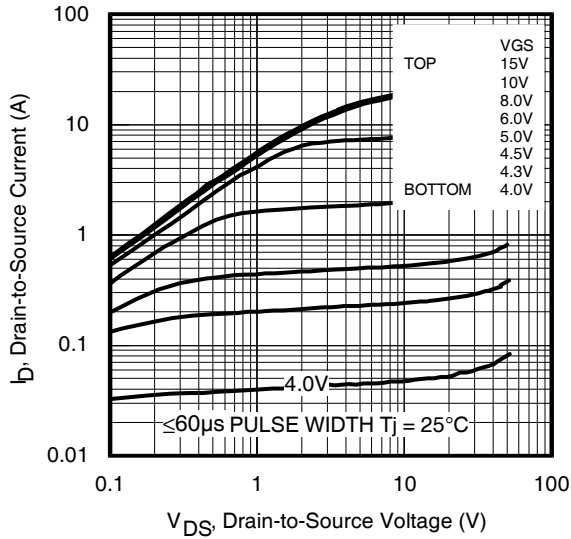
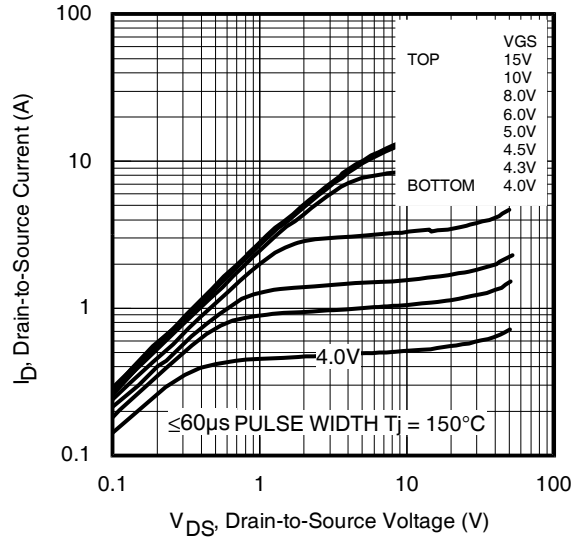
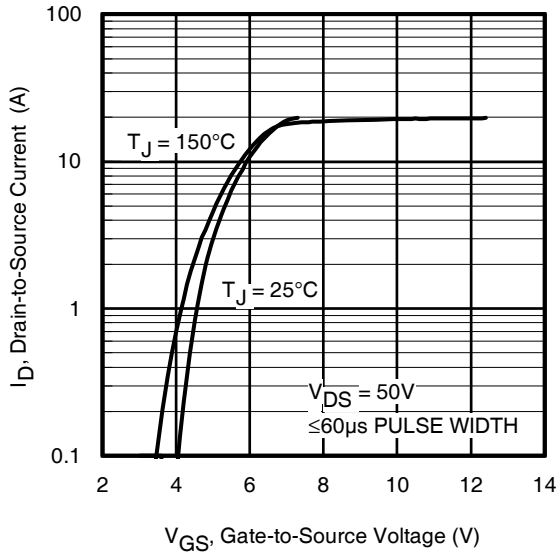
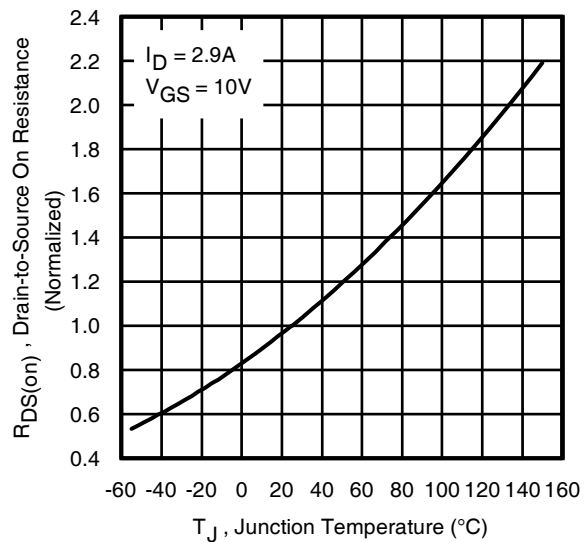
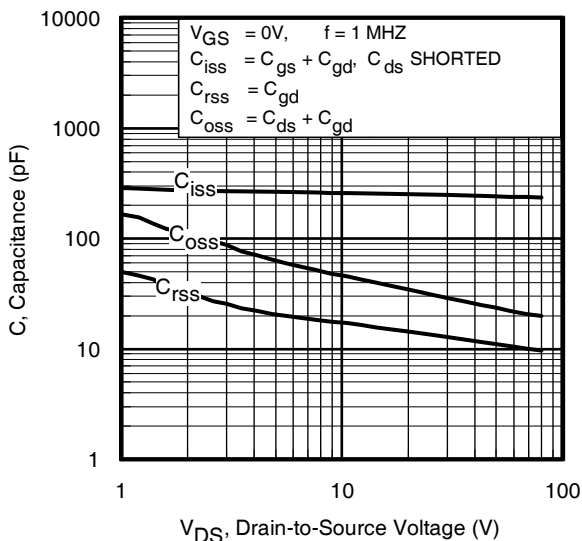
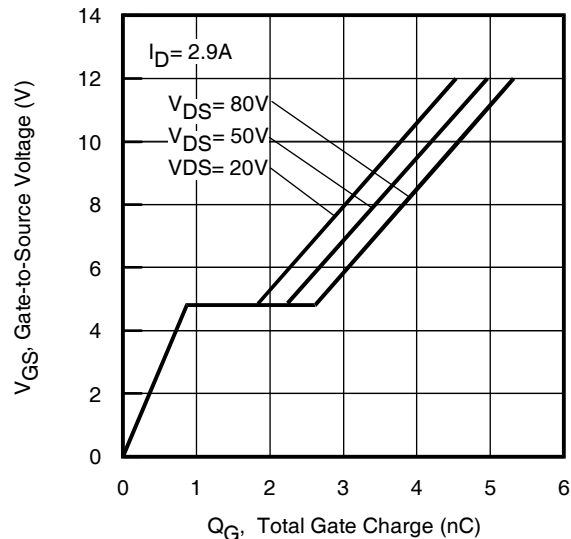
	Parameter	Typ.	Max.	Units
E <sub>AS</sub>	Single Pulse Avalanche Energy ②	—	10.2	mJ
I <sub>AR</sub>	Avalanche Current ①	—	2.9	A

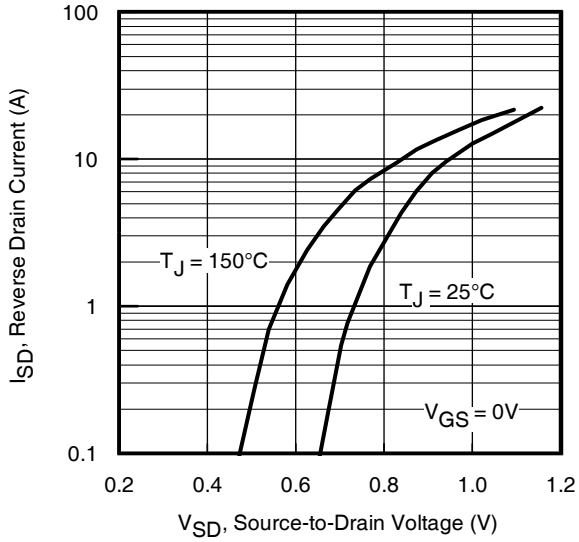
**Diode Characteristics**

	Parameter	Min.	Typ.	Max.	Units	Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)	—	—	3.4⑥	A	MOSFET symbol showing the integral reverse p-n junction diode. 
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①	—	—	14		
V <sub>SD</sub>	Diode Forward Voltage	—	—	1.3	V	T <sub>J</sub> = 25°C, I <sub>S</sub> = 2.9A, V <sub>GS</sub> = 0V ③
t <sub>rr</sub>	Reverse Recovery Time	—	15	23	ns	T <sub>J</sub> = 25°C, I <sub>F</sub> = 2.9A, V <sub>DD</sub> = 50V
Q <sub>rr</sub>	Reverse Recovery Charge	—	45	68	nC	di/dt = 500A/μs ③
t <sub>on</sub>	Forward Turn-On Time	Time is dominated by parasitic Inductance				

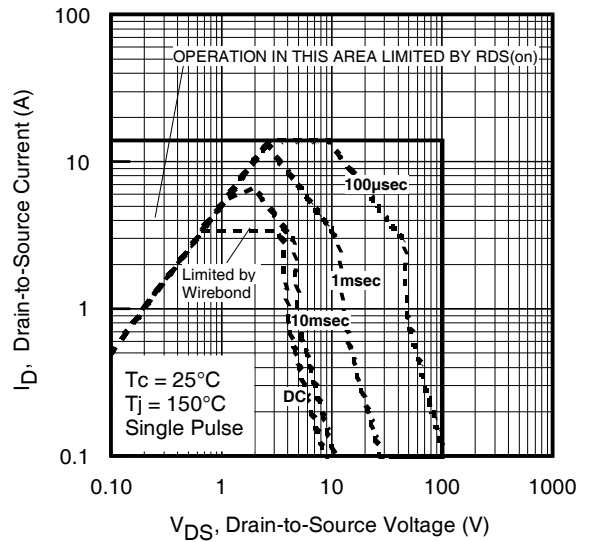
**Thermal Resistance**

	Parameter	Typ.	Max.	Units
R <sub>θJC</sub> (Bottom)	Junction-to-Case ④	—	12	°C/W
R <sub>θJC</sub> (Top)	Junction-to-Case ④	—	85	
R <sub>θJA</sub>	Junction-to-Ambient ⑤	—	55	
R <sub>θJA</sub> (<10s)	Junction-to-Ambient ⑤	—	38	

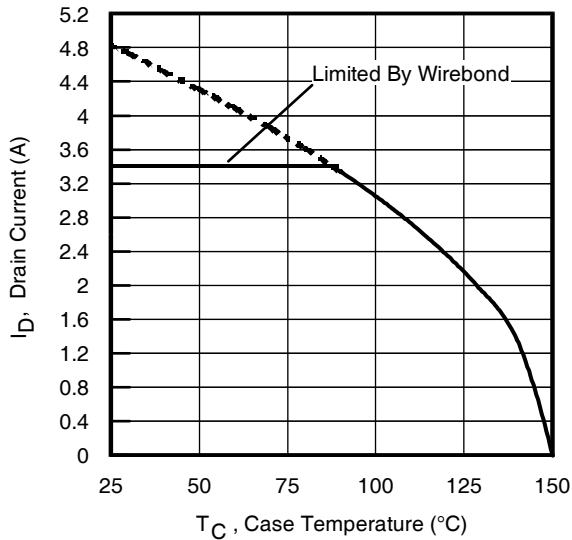

**Fig 1. Typical Output Characteristics**

**Fig 2. Typical Output Characteristics**

**Fig 3. Typical Transfer Characteristics**

**Fig 4. Normalized On-Resistance vs. Temperature**

**Fig 5. Typical Capacitance vs. Drain-to-Source Voltage**

**Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage**



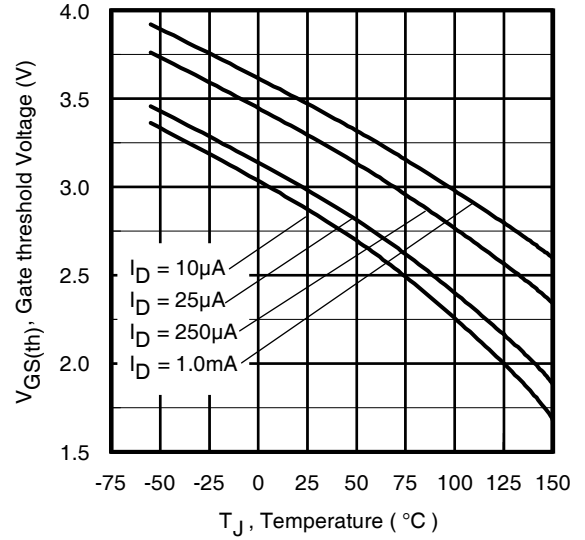
**Fig 7.** Typical Source-Drain Diode Forward Voltage



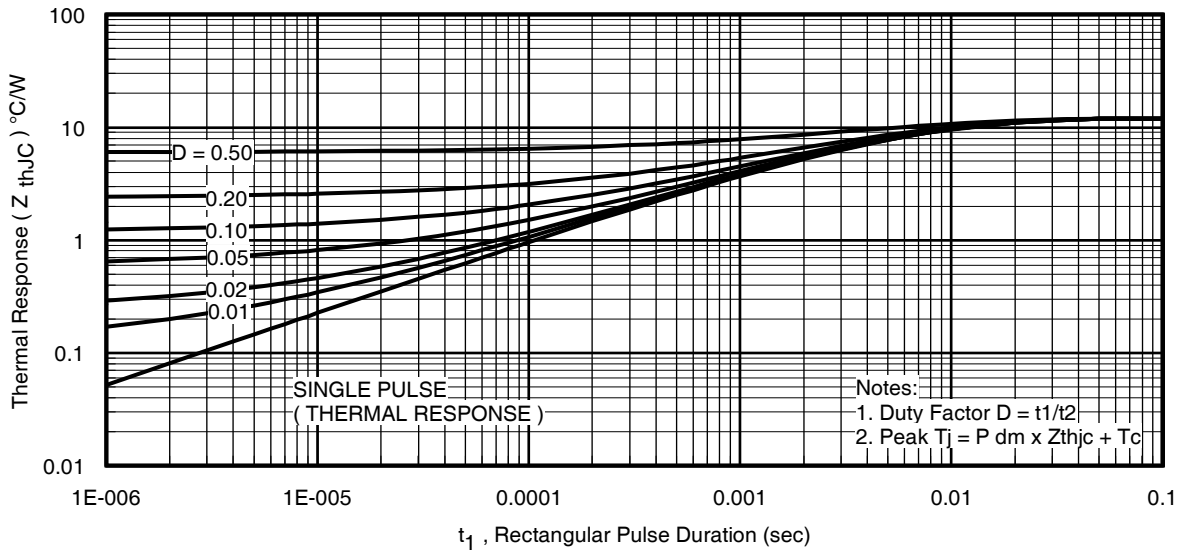
**Fig 8.** Maximum Safe Operating Area



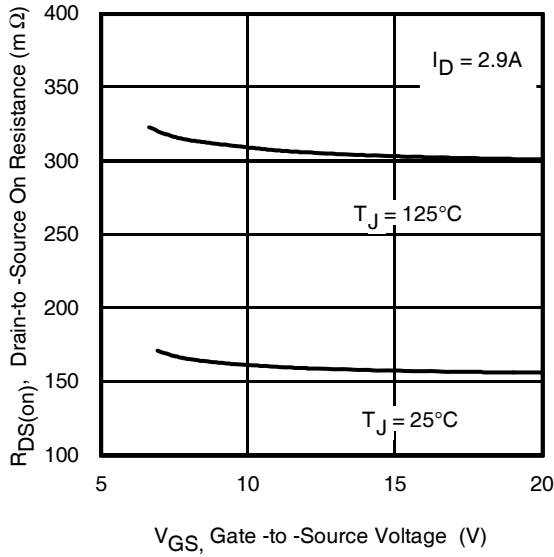
**Fig 9.** Maximum Drain Current vs. Case (Bottom) Temperature



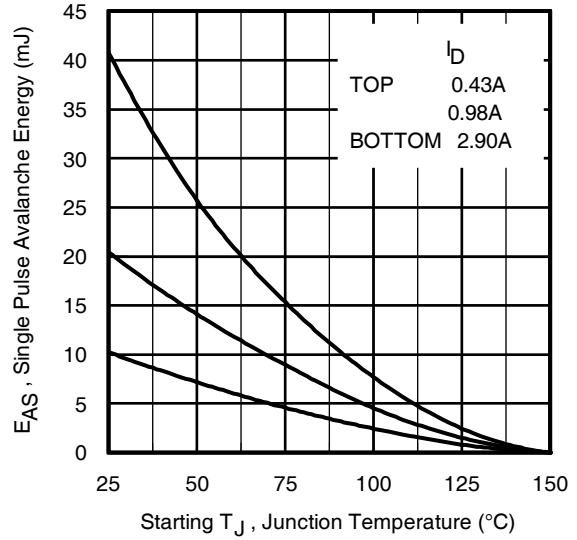
**Fig 10.** Threshold Voltage vs. Temperature



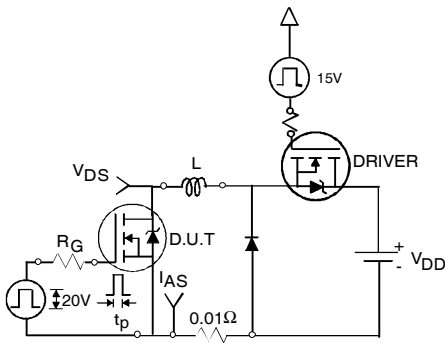
**Fig 11.** Maximum Effective Transient Thermal Impedance, Junction-to-Case (Bottom)



**Fig 12.** On-Resistance vs. Gate Voltage



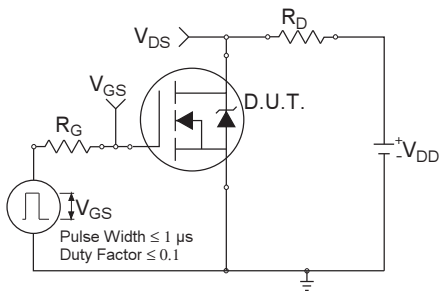
**Fig 13.** Maximum Avalanche Energy vs. Drain Current



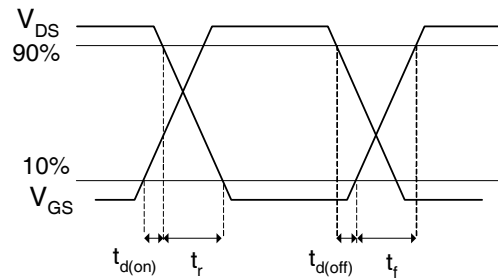
**Fig 14a.** Unclamped Inductive Test Circuit



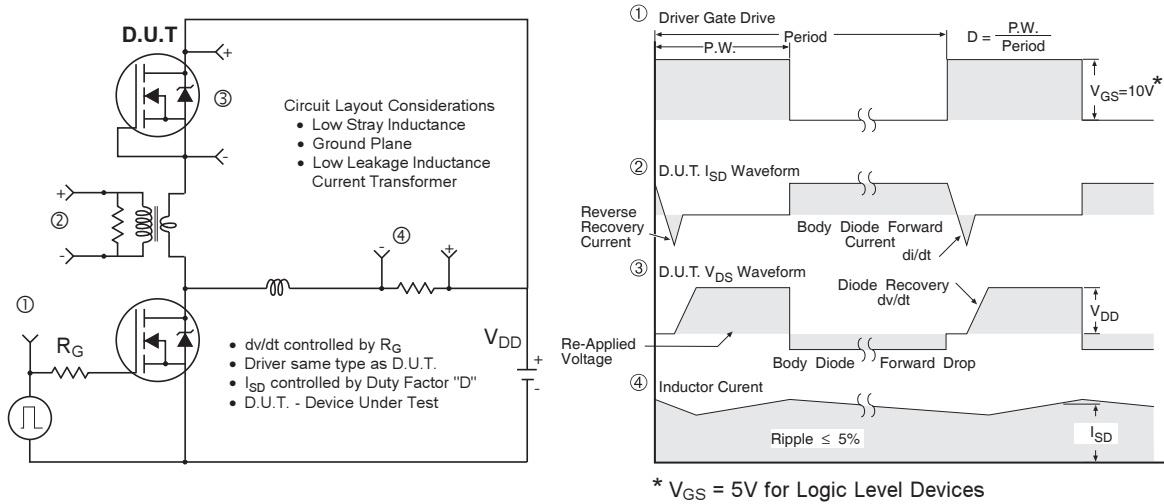
**Fig 14b.** Unclamped Inductive Waveforms



**Fig 15a.** Switching Time Test Circuit



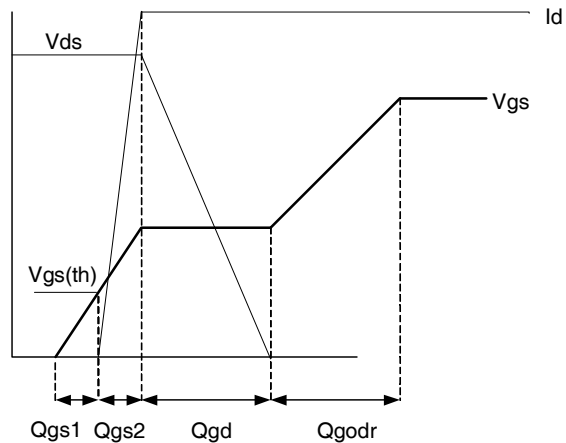
**Fig 15b.** Switching Time Waveforms



**Fig 16. Peak Diode Recovery  $dv/dt$  Test Circuit for N-Channel HEXFET<sup>®</sup> Power MOSFETs**

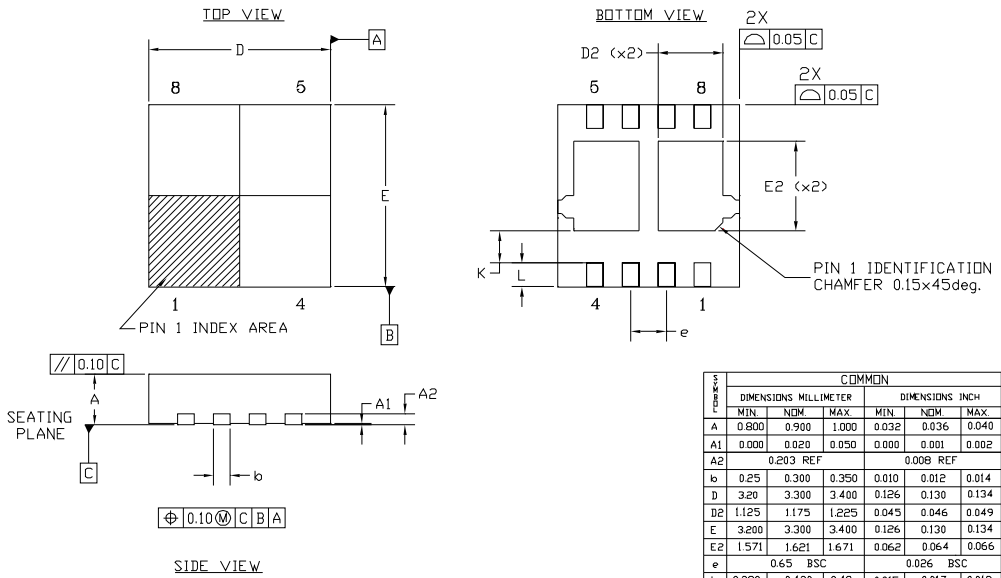


**Fig 17. Gate Charge Test Circuit**



**Fig 18. Gate Charge Waveform**

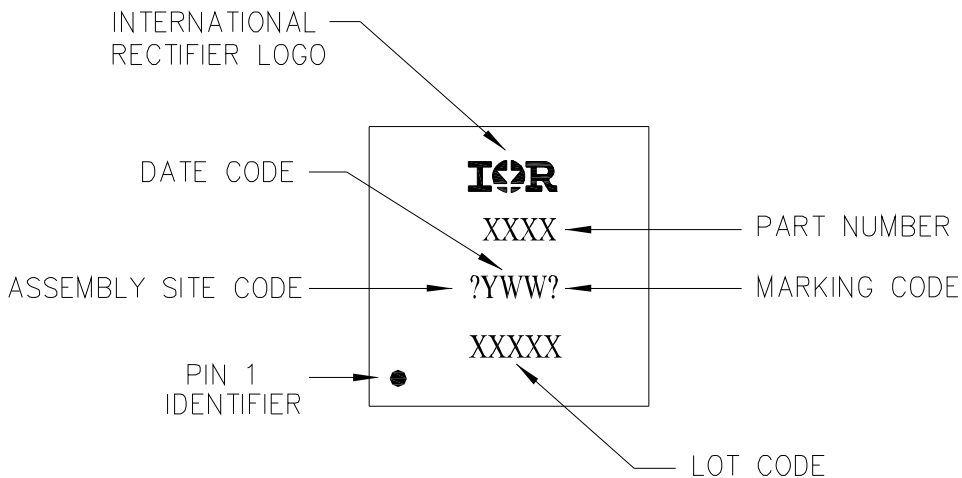
# PQFN Dual 3.3x3.3 Package Details



- NOTES :
1. DIMENSION AND TOLERANCING CONFORM TO ASME Y14.5M-1994.
  2. CONTROLLING DIMENSIONS : MILLIMETER. CONVERTED INCH DIMENSION ARE NOT NECESSARILY EXACT.
  3. DIMENSION b APPLIES TO METALLIZED TERMINAL AND IS MEASURED BETWEEN 0.15 AND 0.30 mm FROM TERMINAL TIP.

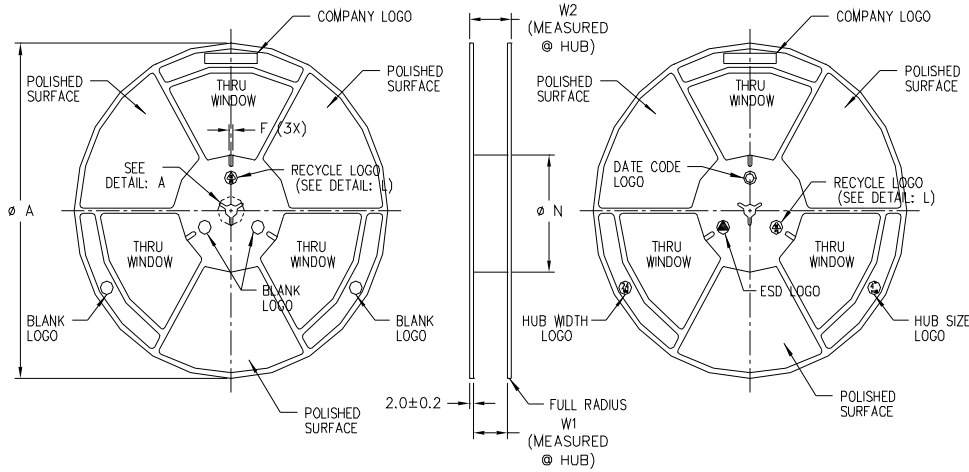
For footprint and stencil design recommendations, please refer to application note AN-1154 at <http://www.irf.com/technical-info/appnotes/an-1154.pdf>

# PQFN Dual 3.3x3.3 Part Marking

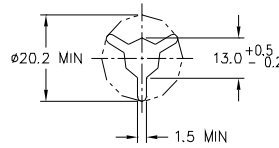


Note: For the most current drawing please refer to IR website at: <http://www.irf.com/package/>

# PQFN Dual 3.3x3.3 Tape and Reel


**NOTES:**

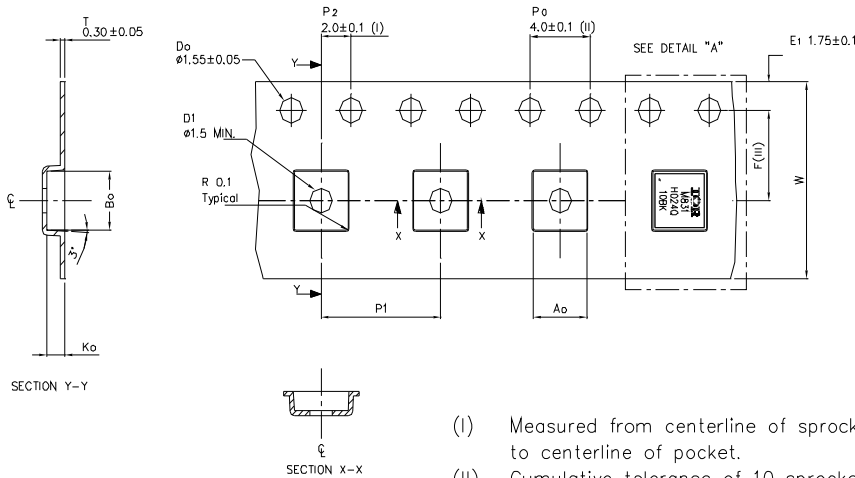
1. GENERIC PRODUCT.
2. FOR PRODUCT DRAWING ONLY.
3. SUNBLAST ALL SURFACE UNLESS OTHERWISE STATED.
4. MOLD 2


**DETAIL: L**

- ANTISTATIC (ALL COLORS)
- STATIC (BLACK)
- DISSIPATIVE (BLACK)
- CONDUCTIVE (BLACK)

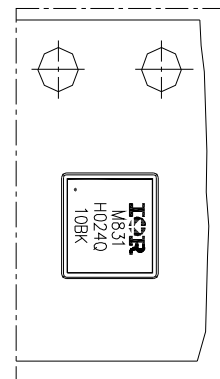
LEGEND	SURFACE SR RANGE	RESISTIVITY TYPE	COLOUR
A	BELOW $10^{12}$	ANTISTATIC	ALL TYPES
B	$10^6$ TO $10^{11}$	STATIC DISSIPATIVE	BLACK ONLY
C	$10^5$ & BELOW $10^5$	CONDUCTIVE (GENERIC)	BLACK ONLY
D	$10^5$ TO $10^9$	CONDUCTIVE (CUSTOM)	BLACK ONLY
E	BELOW $10^{12}$	COATED ANTISTATIC	ALL COLOR

TAPE WIDTH	PRODUCT SPECIFICATION				
	$\phi A \pm 2.0$	$\phi N \pm 2.0$	W1	W2 (MAX)	E (MIN)
08MM	330	100	$8.4^{+1.5}_{-0.0}$	14.4	2.5
12MM	330	100	$12.4^{+2.0}_{-0.0}$	18.4	2.5
16MM	330	100	$16.4^{+2.0}_{-0.0}$	22.4	2.5
24MM	330	100	$24.4^{+2.0}_{-0.0}$	30.4	2.5
32MM	330	100	$32.4^{+2.0}_{-0.0}$	38.4	2.5



Ao	3.60 +/- 0.1
Bo	3.60 +/- 0.1
Ko	1.20 +/- 0.1
F	5.50 +/- 0.1
P1	8.00 +/- 0.1
W	12.00 +/- 0.3

- (I) Measured from centerline of sprocket hole to centerline of pocket.
- (II) Cumulative tolerance of 10 sprocket holes is  $\pm 0.20$ .
- (III) Measured from centerline of sprocket hole to centerline of pocket.
- (IV) Other material available.
- (V) Typical SR of form tape Max  $10^9$  OHM/SQ

**DETAIL "A"**


Note: For the most current drawing please refer to IR website at: <http://www.irf.com/package/>



**Qualification information<sup>†</sup>**

Qualification level	Industrial <sup>††</sup> (per JEDEC JESD47F <sup>†††</sup> guidelines)	
Moisture Sensitivity Level	PQFN Dual 3.3mm x 3.3mm	MSL1 (per JEDEC J-STD-020D <sup>†††</sup> )
RoHS compliant	Yes	

† Qualification standards can be found at International Rectifier's web site  
<http://www.irf.com/product-info/reliability>

†† Higher qualification ratings may be available should the user have such requirements.  
 Please contact your International Rectifier sales representative for further information:  
<http://www.irf.com/whoto-call/salesrep/>

††† Applicable version of JEDEC standard at the time of product release.

**Notes:**

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Starting  $T_J = 25^\circ\text{C}$ ,  $L = 2.43\text{mH}$ ,  $R_G = 50\Omega$ ,  $I_{AS} = 2.9\text{A}$ .
- ③ Pulse width  $\leq 400\mu\text{s}$ ; duty cycle  $\leq 2\%$ .
- ④  $R_\theta$  is measured at  $T_J$  of approximately  $90^\circ\text{C}$ .
- ⑤ When mounted on 1 inch square 2 oz copper pad on 1.5x1.5 in. board of FR-4 material.
- ⑥ Calculated continuous current based on maximum allowable junction temperature. Package is limited to 3.4A by wirebond capability.

**Revision History**

Date	Comments
12/16/2013	<ul style="list-style-type: none"> <li>• Updated ordering information to reflect the End-Of-life (EOL) of the mini-reel option (EOL notice #259)</li> <li>• Updated data sheet with new IR corporate template</li> </ul>